

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	40	inspect\$3 near5 condition and design near5 (information or data) and detect\$3 near5 defects and semiconductor and classif\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/11/10 14:30